

Silicon Germanium Low Noise Amplifier: BGA7L1BN6

Low Noise Amplifier for LTE Band 5 (869 - 894 MHz) using 0201 LQP Inductor

Application Note AN457

About this document

Scope and purpose

This application note describes Infineon's Silicon Germanium Low Noise Amplifier: BGA7L1BN6 as Low Noise Amplifier for LTE Band 5 application (869 - 894 MHz).

- 1. The BGA7L1BN6 is a Silicon Germanium low noise amplifier.
- 2. It covers the LTE application in the frequency range of 869 894 MHz.
- 3. In this report, the performance of BGA7L1BN6 for LTE Band 5 (869 894 MHz) is presented. The circuit uses only one inductor for input matching. The performance is measured on a FR4 board.
- 4. Key performance parameters at 2.8 V, 882 MHz (High Gain Mode)

Noise Figure = 0.89 dBGain = 13.1 dBInput return loss = 13.1 dBOutput return loss = 13.5 dBInput P1dB = -1.5 dBm



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1) The graphs are generated with the simulation program AWR Microwave Office®.



1 Introduction of LTE Application

Mobile phones represent the largest worldwide market in terms of both volume and number of applications on a single platform today. More than 1.5 billion phones are shipped per year worldwide. The major wireless functions in a typical mobile phone include a 2G/3G/4G (GSM/EDGE/CDMA/UMTS/WCDMA/LTE/LTE-A/TD-SCDMA/TD-LTE) cellular modem, and wireless connectivity systems such as Wireless Local Area Network (WLAN), Global Navigation Satellite System (GNSS), broadcasting receivers, and Near-Field Communication (NFC).

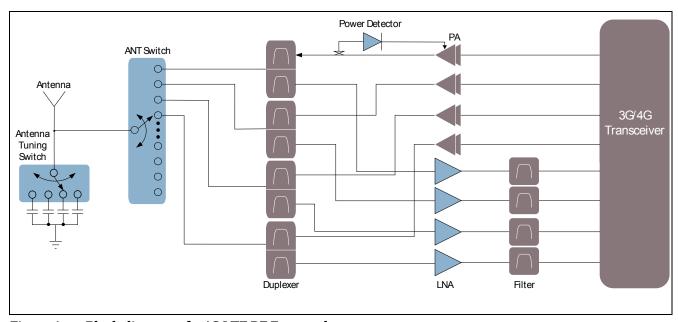


Figure 1 Block diagram of a 4G LTE RF Frontend

Moving towards 4G Long-Term Evolution-Advanced (LTE-A), the number of LTE bands has exploded in the last few years. Currently, there are more than 50 bands in use worldwide. The ability of 4G LTE-A to support single-carrier bandwidth up to 20 MHz and to have more spectral efficiency by using high-order modulation schemes such as Quadrature Amplitude Modulation (QAM-64) is of particular importance as the demand for higher wireless data speeds continues to grow rapidly. LTE-A can aggregate up to 5 carriers (up to 100 MHz) to increase user data rates and capacity for high-speed applications. These new techniques for mobile high-data-rate communication and advanced wireless connectivity include:

- Inter-operation Frequency-Division Duplexing (FDD) and Time-Division Duplexing (TDD) systems
- Down-/uplink Carrier Aggregation (CA)
- LTE-U and LAA at 5 to 6 GHz using link aggregation or carrier aggregation
- Adaptive antenna systems
- Multiple-Input Multiple-Output (MIMO) for RF Front-Ends
- Device-to-Device (D2D) communication with LTE (LTE-D)



- High-speed wireline connection with USB 3.0, Bluetooth 4.0 etc.

The above mentioned techniques drive the industry to develop new concepts for RF Front-Ends and the antenna system and digital interface protection. These require microwave semiconductor vendors to offer highly integrated and compact devices with lower loss rates, and more powerful linear performance. The key trends in RF components for mobile phone are:

- Microwave Monolithic Integrated Circuits (MMICs) with smaller form factors
- Higher levels of integration with control buses
- Higher RF power capability
- Ability to handle increased number of bands and operating modes
- Better immunity to interfering signals
- Frequency tuning ability
- Higher integration of various functions in single packages (modulization)

Band No.	Band Definition	Uplink Frequency Range	Downlink Frequency Range	FDD/TDD System	Comment
1	Mid-Band	1920-1980 MHz	2110-2170 MHz	FDD	
2	Mid-Band	1850-1910 MHz	1930-1990 MHz	FDD	
3	Mid-Band	1710-1785 MHz	1805-1880 MHz	FDD	
4	Mid-Band	1710-1755 MHz	2110-2155 MHz	FDD	
5	Low-Band	824-849 MHz	869-894 MHz	FDD	
6	Low-Band	830-840 MHz	875-885 MHz	FDD	
7	High-Band	2500-2570 MHz	2620-2690 MHz	FDD	
8	Low-Band	880-915 MHz	925-960 MHz	FDD	
9	Mid-Band	1749.9-1784.9 MHz	1844.9-1879.9 MHz	FDD	
10	Mid-Band	1710-1770 MHz	2110-2170 MHz	FDD	
11	Mid-Band	1427.9-1452.9 MHz	1475.9-1500.9 MHz	FDD	
12	Low-Band	698-716 MHz	728-746 MHz	FDD	
13	Low-Band	777-787 MHz	746-756 MHz	FDD	
14	Low-Band	788-798 MHz	758-768 MHz	FDD	
15		reserved	reserved	FDD	
16		reserved	Reserved	FDD	
17	Low-Band	704-716 MHz	734-746 MHz	FDD	
18	Low-Band	815-830 MHz	860-875 MHz	FDD	
19	Low-Band	830-845 MHz	875-890 MHz	FDD	
20	Low-Band	832-862 MHz	791-821 MHz	FDD	
21	Mid-Band	1447.9-1462.9 MHz	1495.9-1510.9 MHz	FDD	
22	High-Band	3410-3500 MHz	3510-3600 MHz	FDD	
23	Mid-Band	2000-2020 MHz	2180-2200 MHz	FDD	
24	Mid-Band	1626.5-1660.5 MHz	1525-1559 MHz	FDD	



Band No.	Band Definition	Uplink Frequency Range	Downlink Frequency Range	FDD/TDD System	Comment			
25	Mid-Band	1850-1915 MHz	1930-1995 MHz	FDD				
26	Low-Band	814-849 MHz	859-894 MHz	FDD				
27	Low-Band	807-824 MHz	852-869 MHz	FDD				
28	Low-Band	703-748 MHz	758-803 MHz	FDD				
29	Low-Band	N/A	716-728 MHz	FDD				
30	High-Band	2305-2315 MHz	2350-2360 MHz	FDD				
31	Low-Band	452.5-457.5 MHz	462.5-467.5MHz	FDD				
32	Mid-Band	N/A	1452-1496 MHz	FDD				
33	Mid-Band	1900-19	920 MHz	TDD				
34	Mid-Band	2010-20	025 MHz	TDD				
35	Mid-Band	1850-19	1850-1910 MHz					
36	Mid-Band	1930-19	TDD					
37	Mid-Band	1910-19	TDD					
38	High-Band	2570-20	TDD					
39	Mid-Band	1880-19	TDD					
40	High-Band	2300-24	TDD					
41	High-Band	2496-20	TDD					
42	High-Band	3400-3	TDD					
43	High-Band	3600-38	800 MHz	TDD				
44	Low-Band	703-80	03 MHz	TDD				
45	Mid-Band	1447-14	TDD					
46	Ultra High-Band	5150-59	TDD					
64		Rese						
65	Mid-Band	1920-2010 MHz 2110-2200 MHz		FDD				
66	Mid-Band	1710-1780 MHz	2110-2200 MHz	FDD				
67	Low-Band	N/A	738-758 MHz	FDD				
68	Low-Band	698-728 MHz	FDD					

Note: FDD - Frequency Division Duplexing; TDD - Time Division Duplexing.

1.1 Key Requirements on LNAs in LTE Applications

The LTE-Advanced supports data rates of up to 1 Gbps with advanced techniques such as Multiple Input Multiple Output and Carrier Aggregation. LTE-Advanced can support up to 5 bands of carrier aggregation by three component carrier aggregation scenarios: Intra-band contiguous, intra-band non-contiguous and inter-band non-contiguous aggregation. They present new challenges to RF FE designers, such as interference from co-existing bands and harmonic generation. Smart LTE LNAs with the following features can address these requirements to achieve outstanding performance.





Low Noise Figure (NF): An external LNA or LNA module boosts the sensitivity of the system by reducing the overall NF. In addition due to the size constraint, the modem antenna and the receiver FE cannot always be placed close to the transceiver Integrated Circuit (IC). The path loss in front of the integrated LNA on the transceiver IC increases the system NF significantly. An external LNA physically close to the antenna can help to eliminate the path loss and reduce the system NF. The sensitivity can be improved by several dB, which means a significant increase in the connectivity range.

High Linearity (1-dB compression point P1dB and 3rd-order intercept point IP3): An increased number of bands at the receiver input create strong interference, leading to high requirements in linearity characteristics such as high input 1-dB compression point, 2rd intermodulation (IMD2) products and input IP3 performance.

Low Power Consumption: Power consumption is even more important in today's smartphones. The latest LTE-Advanced uses enhanced MIMO techniques with up to 8 streams for downlink and 4 streams for uplink. Infineon's LNAs and LNA modules have low supply current and an integrated on/off feature that reduces power consumption and increases standby time for cellular handsets or other portable battery-operated wireless applications.

High Integration and Simple Control Interface: The demand for size and cost reduction and performance enhancement with ease of use and low parts count has become very important in existing and future generation smartphones. Our MMIC LNAs are highly integrated with input and output either matched or pre-matched, built-in temperature and supply voltage stabilization, and a fully ESD-protected circuit design to ensure stable operation and a simple control interface.

More information on the LTE LNAs is available at: www.infineon.com/ltelna

More information on the Mobile Phone RF Frontend and related Infineon product portfolio are available in the Application Guide Mobile Communication: www.infineon.com/appguide_rf_mobile



BGA7L1BN6 Overview

2 BGA7L1BN6 Overview

2.1 Features

• High insertion power gain: 13.6 dB

• Low noise figure: 0.75 dB

• Low current consumption: 4.9 mA

• Operating frequencies: 716 –960 MHz

• Two-state control: Bypass- and High gain-Mode

Supply voltage: 1.5 V to 3.6 V

• Digital on/off switch (1 V logic high level)

• Ultra small TSNP-6-2 leadless package (footprint: 0.7 x 1.1 mm²)

B7HF Silicon Germanium technology

• RF output internally matched to 50Ω

• Only 1 external SMD component necessary

• 2 kV HBM ESD protection (including AI-pin)

• Pb-free (RoHS compliant) package





Figure 2 BGA7L1BN6 in TSNP-6-2

2.2 Description

The BGA7L1BN6 is a front-end low noise amplifier for LTE which covers a wide frequency range from 716 MHz to 960 MHz. The LNA provides 13.4 dB gain and 0.89 dB noise figure at a current consumption of 5.1 mA in the application configuration described in **Chapter 3**. In bypass mode the LNA provides an insertion loss of -2.4 dB. The BGA7L1BN6 is based upon Infineon Technologies'B7HF Silicon Germanium technology. It operates from 1.5 V to 3.3 V supply voltage. The device features a single-line two-state control (Bypass- and High gain-Mode) and can be controlled via several Infineon devices, e.g. BGAC600. OFF-state can be enabled by powering down Vcc. Please contact Infineon Technologies to get the latest list of available devices which can control this LNA.



BGA7L1BN6 Overview

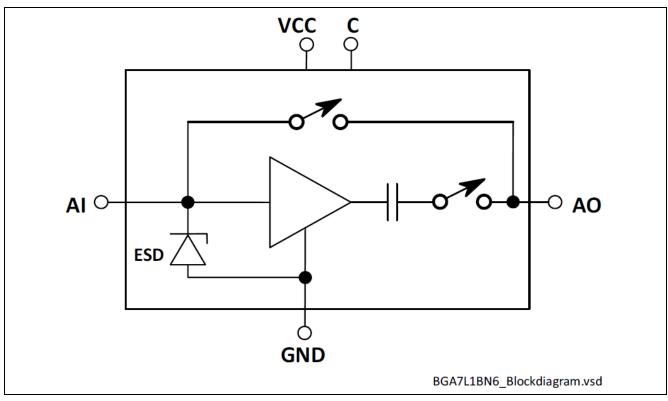


Figure 3 Equivalent Circuit Block diagram of BGA7L1BN6

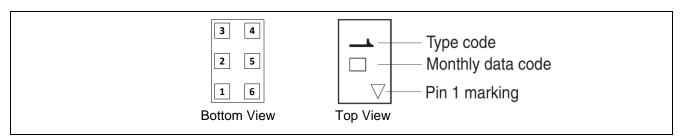


Figure 4 Package and pin connections of BGA7L1BN6

Table 1 Pin Assignment of BGA7L1BN6

Pin No.	Symbol	Function
1	GND	Ground
2	VCC	DC supply
3	AO	LNA output
4	GND	Ground
5	AI	LNA input
6	С	Control



3 Application Circuit and Performance Overview

In this chapter the performance of the application circuit, the schematic and bill-of-materials are presented.

Device: BGA7L1BN6

Application: Low Noise Amplifier for LTE Band 5 Applications using 0201 LQP inductor

PCB Marking: M150429 EVB Order No.: AN457

3.1 Summary of Measurement Results

The performance of BGA7L1BN6 for LTE LNA Band 5 ($869-894\,\mathrm{MHz}$) is summarized in the following tables.

Table 2 Electrical Characteristics of the BGA7L1BN6 (at room temperature) for LTE Band 5 in High Gain Mode

Parameter	Symbol			Va	Unit	Comment/Test Condition			
DC Voltage	Vcc		1.8			2.8		V	
DC Current	Icc		4.5			5.1		mA	
Frequency Range	Freq	869	882	894	869	882	894	MHz	
Gain	G	13.1	13.0	12.8	13.5	13.4	13.3	dB	
Noise Figure	NF	0.94	0.91	0.90	0.93	0.89	0.89	dB	Loss of input line 0.05 dB deembedded
Input Return Loss	RLin	12.1	12.0	11.9	13.1	13.1	12.4	dB	
Output Return Loss	RLout	13.3	13.0	12.7	13.9	13.5	13.2	dB	
Reverse Isolation	IRev	20.5	20.4	20.3	20.9	20.8	20.7	dB	
Input P1dB	IP1dB	-4.6	-4.5	-4.2	-1.7	-1.5	-1.5	dBm	
Output P1dB	OP1dB	8.5	8.5	8.6	11.8	11.9	11.8	dBm	
Input IP3	IIP3		5.0		5.0			dBm	$f_1 = 882 \text{ MHz}$
Output IP3	OIP3		18.0		18.4		dBm	$f_2 = 883 \text{ MHz}$ $P_{in} = -30 \text{ dBm}$	
Stability	k	>1					1	Unconditionally stable from 0 to 10 GHz	



Table 3 Electrical Characteristics of the BGA7L1BN6 (at room temperature) for LTE Band 5 in Bypass Mode

Parameter	Symbol			Va	Unit	Comment/Test Condition			
DC Voltage	Vcc		1.8			2.8		V	
DC Current	Icc		64			87		uA	
Frequency Range	Freq	869	882	894	869	882	894	MHz	
Gain	G	-2.4	-2.4	-2.5	-2.3	-2.4	-2.4	dB	
Noise Figure	NF	2.88	1.46	0.63	2.78	1.41	0.60	dB	Loss of input line 0.05 dB deembedded
Input Return Loss	RLin	9.8	9.5	9.2	9.6	9.3	9.1	dB	
Output Return Loss	RLout	8.2	7.9	8.0	8.3	8.1	8.0	dB	
Reverse Isolation	IRev	2.4	2.4	2.5	2.3	2.4	2.4	dB	
Input P1dB	IP1dB	6.3	6.6	6.4	7.0	7.4	7.3	dBm	
Output P1dB	OP1dB	3.9	4.2	3.9	4.7	5.0	4.9	dBm	
Input IP3	IIP3		16.2		18.3			dBm	$f_1 = 882 \text{ MHz}$
Output IP3	OIP3		13.8 15.9			dBm	$f_2 = 883 \text{ MHz}$ $P_{in} = -20 \text{ dBm}$		
Stability	k	>1					-	Unconditionally stable from 0 to 10 GHz	



3.2 Summary BGA7L1BN6 as 869 – 894 MHz LNA for LTE Band 5

The BGA7L1BN6 is a Silicon Germanium Low Noise Amplifier for LTE RF frontend in the range from 869 – 894 MHz. In this application note, the performance of BGA6L1BN6 for LTE Band 5 is investigated at 1.8 V and 2.8 V supply voltages. The circuit targets to use as few components as possible, and uses a high quality factor inductor for matching.

At 1.8 V, high gain mode, the BGA7L1BN6 achieves a noise figure of about 0.91 dB and a gain of 13.0 dB. The input return loss is 12.0 dB and output return loss is 13.0 dB at 882 MHz. It obtains an input 1dB Compression Point (IP1dB) of -4.5 dBm at 882 MHz. Using two tones of – 30 dBm spacing 1 MHz; the circuit achieves an input Third-order Intercept Point (IIP3) of 5.0 dBm at 882 MHz.

At 1.8 V, bypass mode, the BGA7L1BN6 achieves an insertion loss of 2.4 dB. The input return loss is 9.5 dB and output return loss is 7.9 dB at 882 MHz. It obtains an input 1dB Compression Point (IP1dB) of 6.6 dBm at 882 MHz. Using two tones of – 20 dBm spacing 1 MHz; the circuit achieves an input Third-order Intercept Point (IIP3) of 16.2 dBm at 882 MHz.

At 2.8 V, high gain mode, the BGA7L1BN6 achieves a noise figure of 0.89 dB and a gain of 13.4 dB. The input return loss is 13.1 dB and output return loss is 13.5 dB at 882 MHz. It obtains an input 1dB Compression Point (IP1dB) of -1.5 dBm at 882 MHz. Using two tones of – 30 dBm spacing 1 MHz; the circuit achieves an input Third-order Intercept Point (IIP3) of 5.0 dBm at 882 MHz.

At 2.8 V, bypass mode, the BGA7L1BN6 achieves an insertion loss of 2.4 dB. The input return loss is 9.3 dB and output return loss is 8.1 dB at 882 MHz. It obtains an input 1dB Compression Point (IP1dB) of 7.4 dBm at 882 MHz. Using two tones of – 20 dBm spacing 1 MHz; the circuit achieves an input Third-order Intercept Point (IIP3) of 18.3 dBm at 882 MHz. The circuit is unconditionally stable up to 10 GHz.



3.3 Schematics and Bill-of-Materials

The schematic of BGA7L1BN6 for LTE Band 5 is presented in **Figure 5** and its bill-of-materials is shown in **Table 4**.

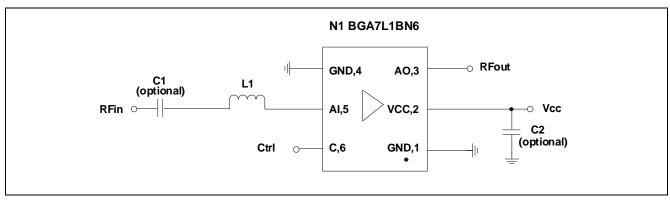


Figure 5 Schematics of the BGA7L1BN6 Application Circuit

Table 4 Bill-of-Materials

Symbol	Value	Unit	Size	Manufacturer	Comment
C1(optional)	1	nF	0201	Various	DC block
C2(optional)	1	nF	0201	Various	RF bypass
L1	9.1	nН	0201	Murata LQP Type	Input matching
N1	BGA7L1BN 6		TSNP-6-2	Infineon	SiGe LNA
PCB					Rogers4003

Note: DC block function is NOT integrated at input of BGA7L1BN6. The DC block capacitor C1 is not necessary if the DC block function on the RF input line can be ensured by the previous stage.

Note: The RF bypass capacitor C2 at the DC power supply pin filters out the power supply noise and stabilizes the DC supply. The RF bypass capacitor C2 is not necessary if a clean and stable DC supply can be ensured.

4 Measurement Graphs

4.1 High Gain Mode

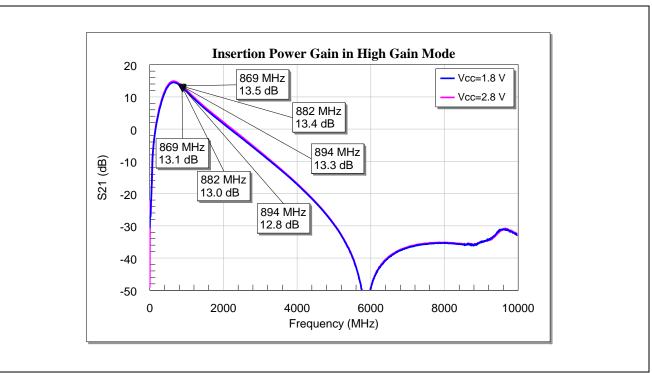


Figure 6 Wideband Insertion Power Gain of the BGA7L1BN6 for LTE Band 5 in High Gain Mode

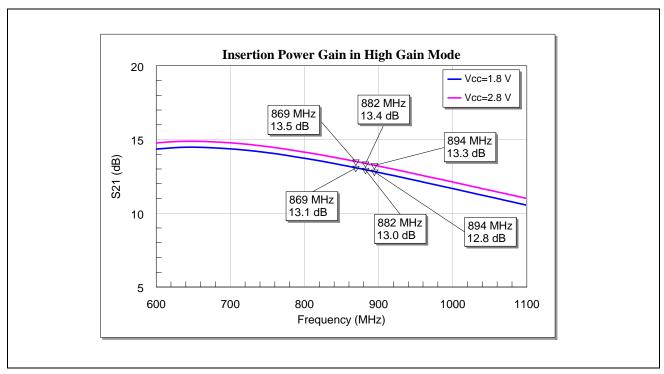


Figure 7 Narrowband Insertion Power Gain of the BGA7L1BN6 for LTE Band 5 in High Gain Mode



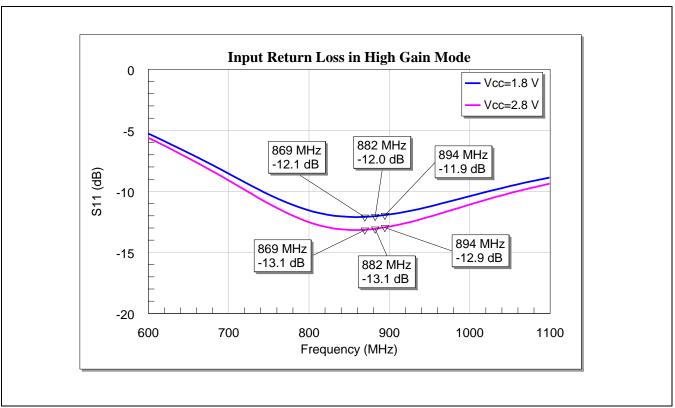


Figure 8 Input Matching of the BGA7L1BN6 for LTE Band 5 in High Gain Mode

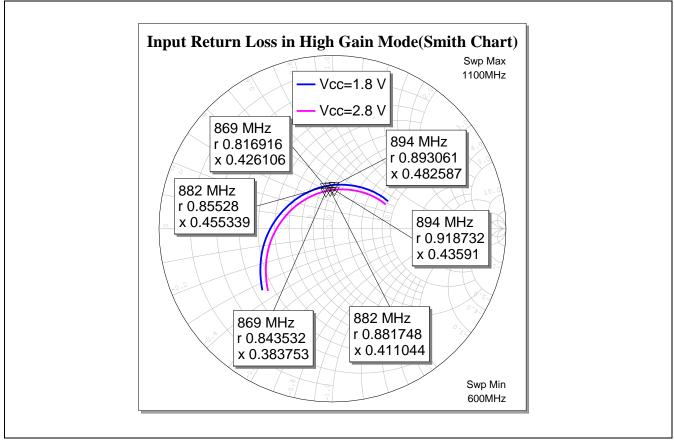


Figure 9 Input Matching (Smith Chart) of the BGA7L1BN6 for LTE Band 5 in High Gain Mode



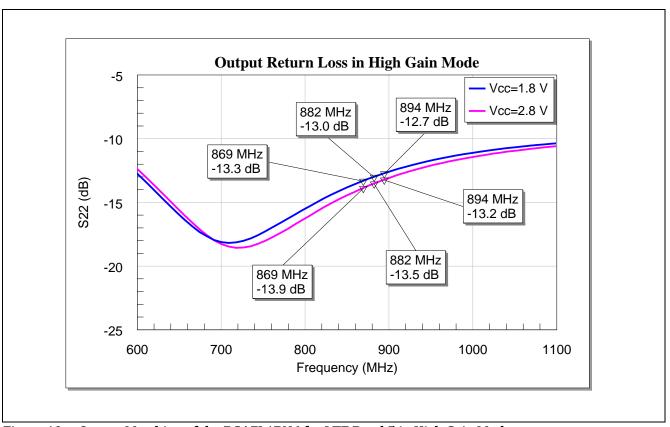


Figure 10 Output Matching of the BGA7L1BN6 for LTE Band 5 in High Gain Mode

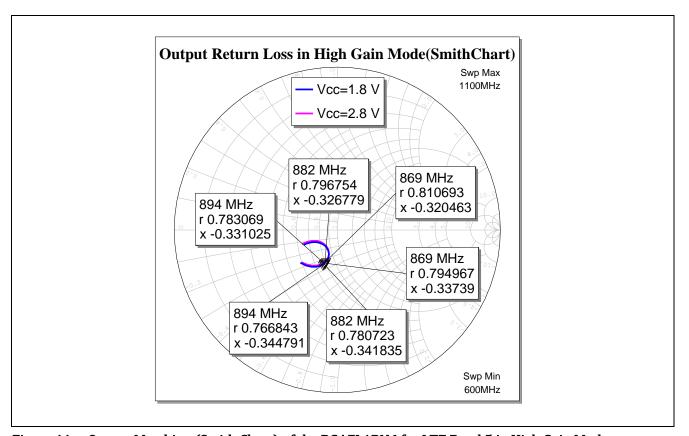


Figure 11 Output Matching (Smith Chart) of the BGA7L1BN6 for LTE Band 5 in High Gain Mode



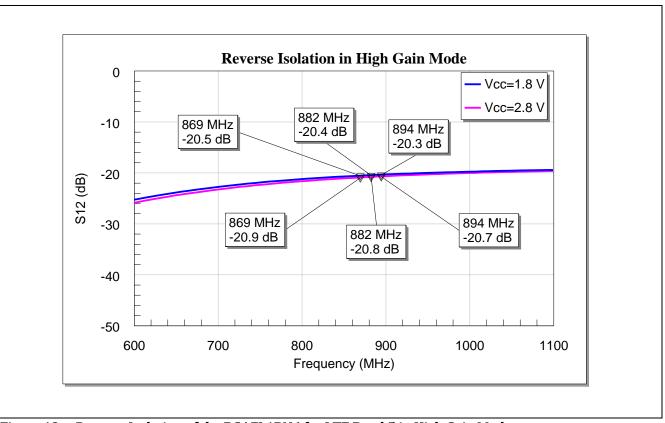


Figure 12 Reverse Isolation of the BGA7L1BN6 for LTE Band 5 in High Gain Mode

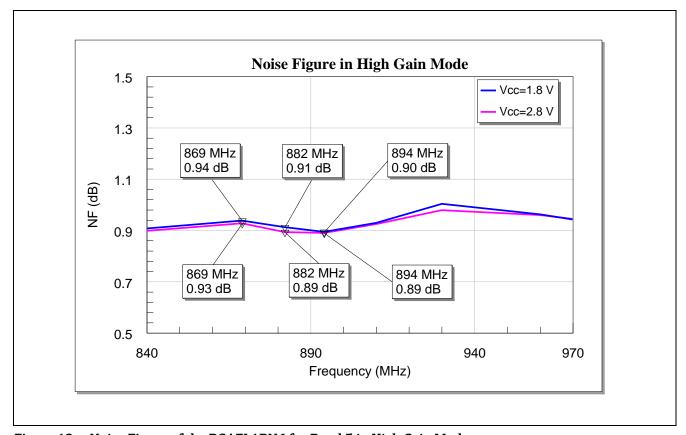


Figure 13 Noise Figure of the BGA7L1BN6 for Band 5 in High Gain Mode



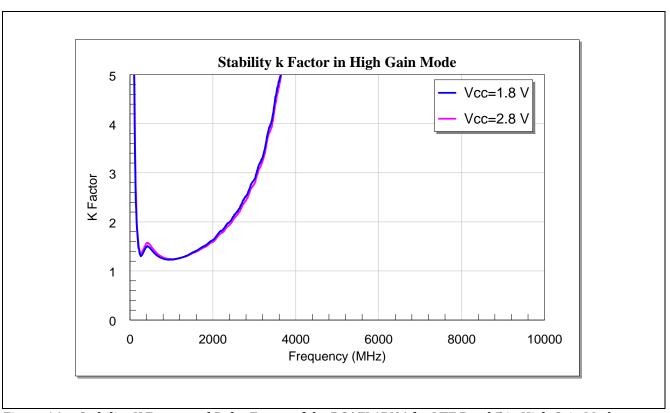


Figure 14 Stability K Factor and Delta Factor of the BGA7L1BN6 for LTE Band 5 in High Gain Mode

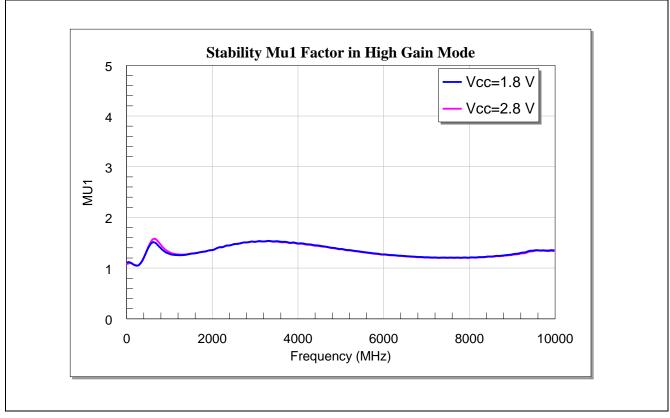


Figure 15 Stability µ1 Factor of the BGA7L1BN6 for LTE Band 5 in High Gain Mode



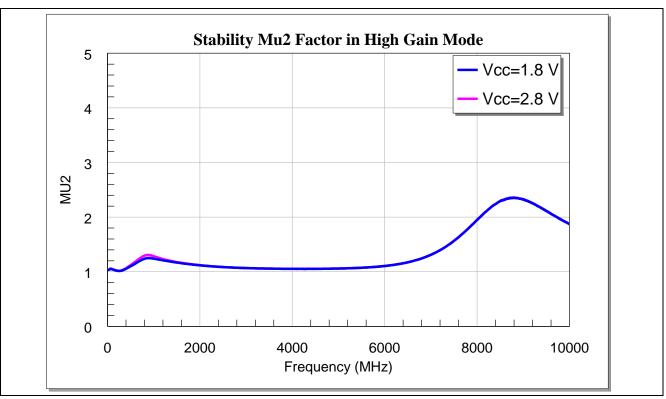


Figure 16 Stability µ2 Factor of the of the BGA7L1BN6 for LTE Band 5 in High Gain Mode

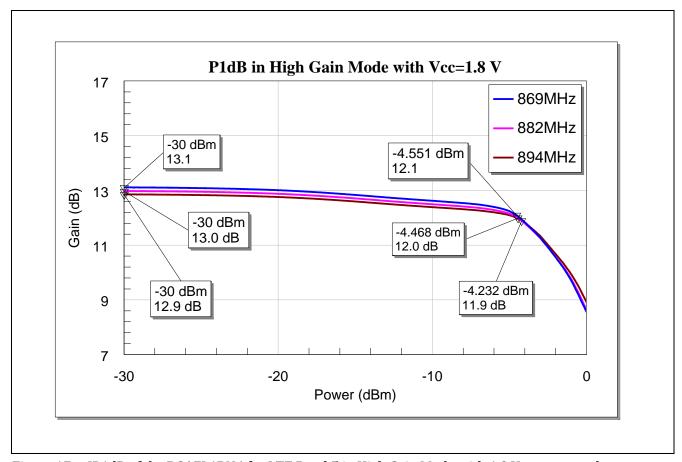


Figure 17 IP1dB of the BGA7L1BN6 for LTE Band 5 in High Gain Mode with 1.8 V power supply



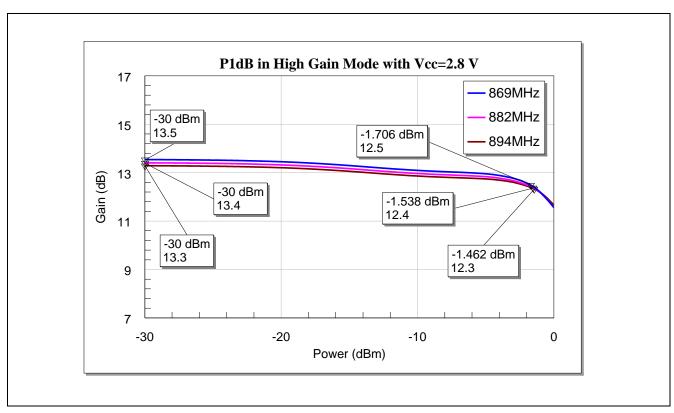


Figure 18 IP1dB of the BGA7L1BN6 for LTE Band 5 in High Gain Mode with 2.8 V power supply

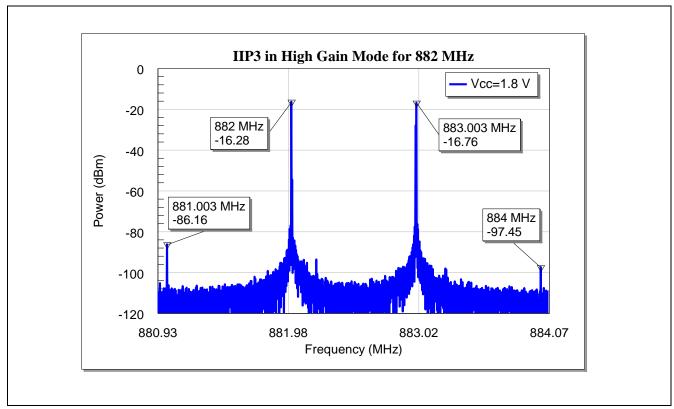


Figure 19 IIP3 of the BGA7L1BN6 for LTE Band 5 in High Gain Mode with 1.8 V power supply



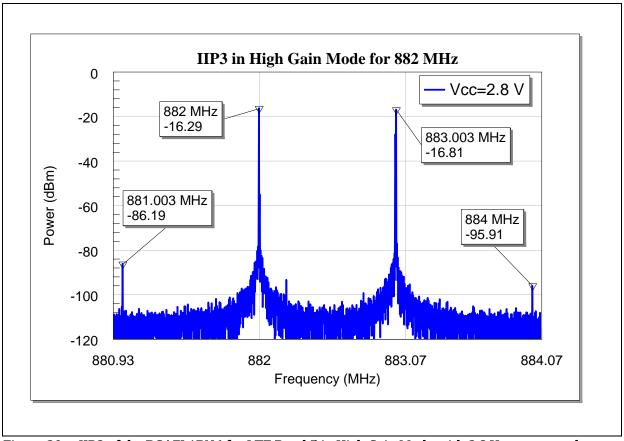


Figure 20 IIP3 of the BGA7L1BN6 for LTE Band 5 in High Gain Mode with 2.8 V power supply



4.2 Bypass Mode

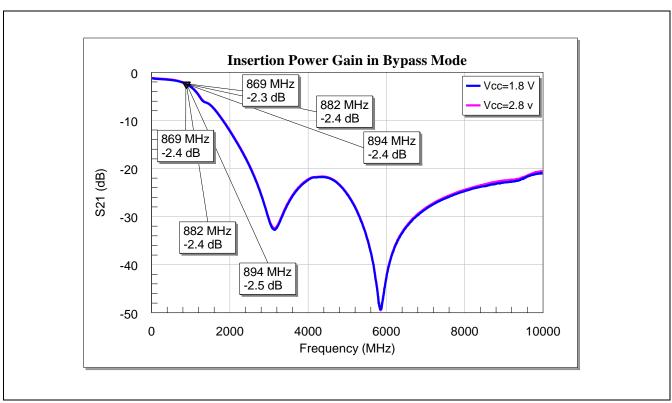


Figure 21 Wideband Insertion Power Gain of the BGA7L1BN6 for LTE Band 5 in Bypass Mode

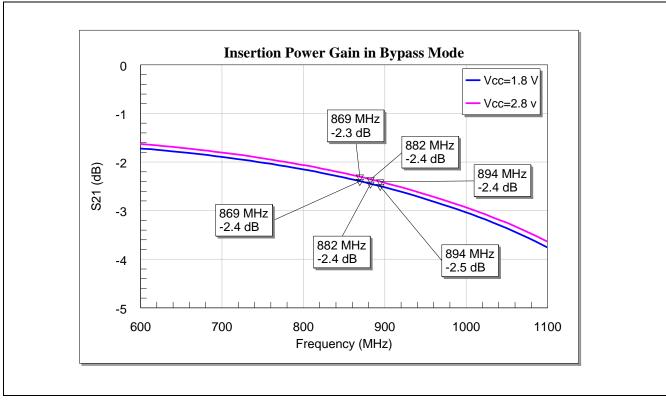


Figure 22 Narrowband Insertion Power Gain of the BGA7L1BN6 for LTE Band 5 in Bypass Mode



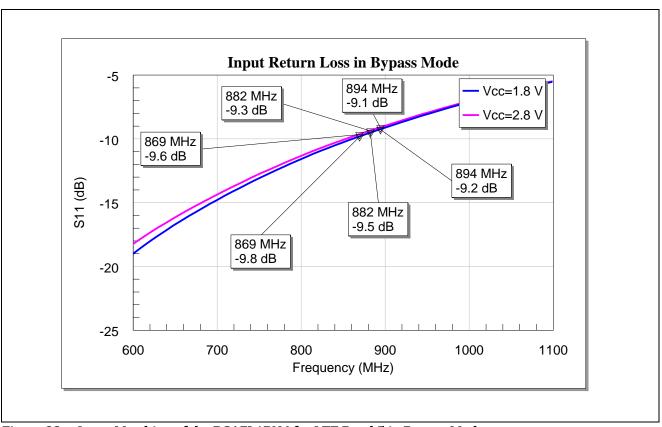


Figure 23 Input Matching of the BGA7L1BN6 for LTE Band 5 in Bypass Mode

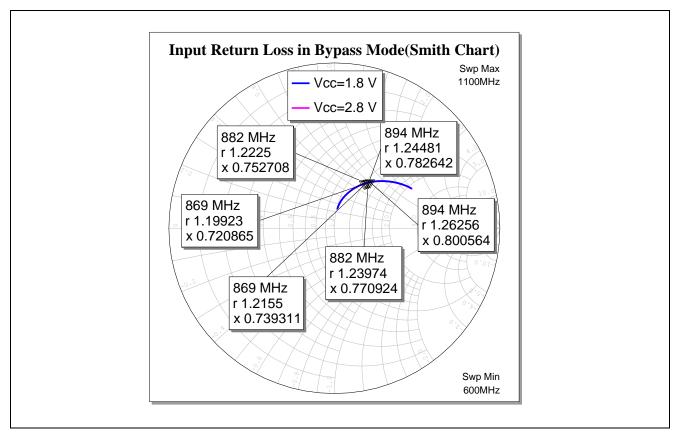


Figure 24 Input Matching (Smith Chart) of the BGA7L1BN6 for LTE Band 5 in Bypass Mode



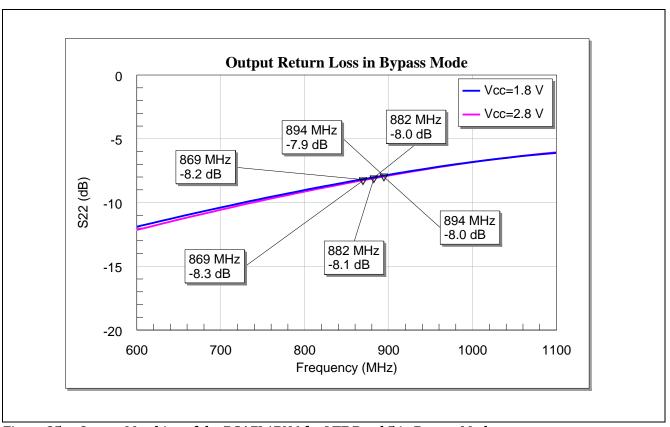


Figure 25 Output Matching of the BGA7L1BN6 for LTE Band 5 in Bypass Mode

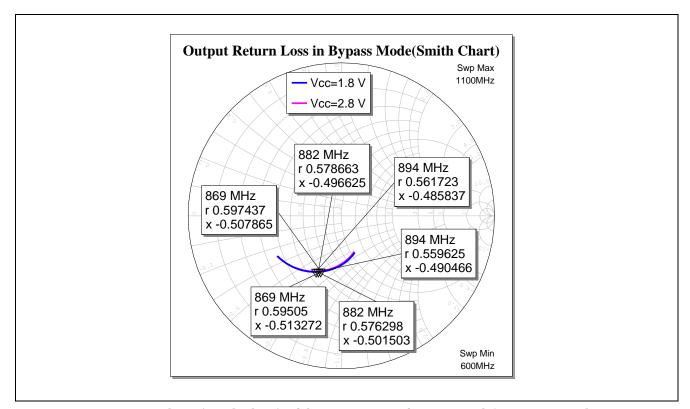


Figure 26 Output Matching (Smith Chart) of the BGA7L1BN6 for LTE Band 5 in Bypass Mode



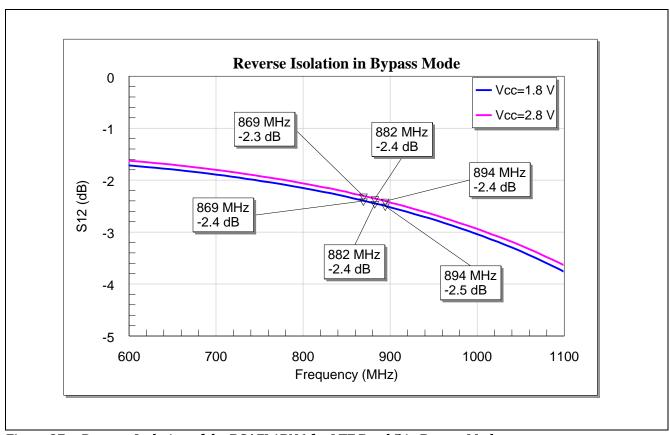


Figure 27 Reverse Isolation of the BGA7L1BN6 for LTE Band 5 in Bypass Mode

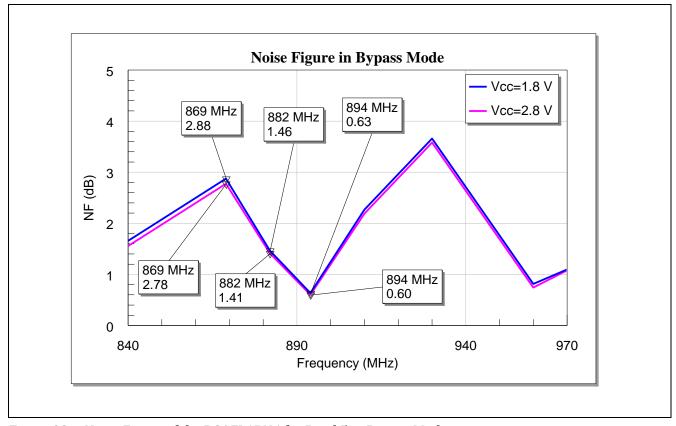


Figure 28 Noise Figure of the BGA7L1BN6 for Band 5 in Bypass Mode



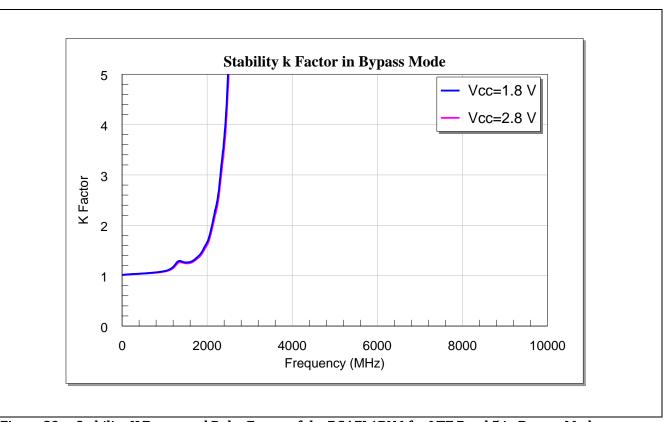


Figure 29 Stability K Factor and Delta Factor of the BGA7L1BN6 for LTE Band 5 in Bypass Mode

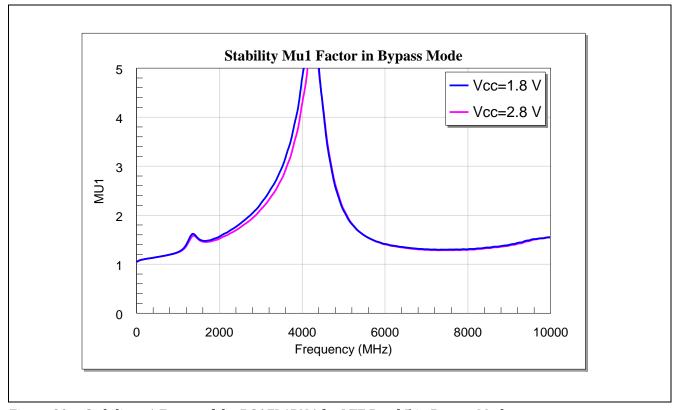


Figure 30 Stability $\mu 1$ Factor of the BGA7L1BN6 for LTE Band 5 in Bypass Mode



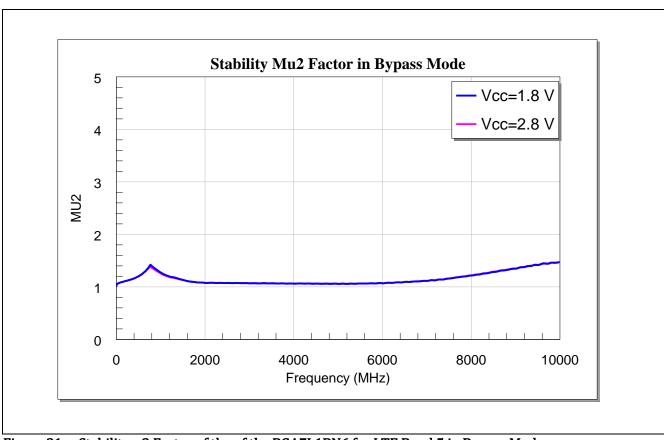


Figure 31 Stability μ 2 Factor of the BGA7L1BN6 for LTE Band 5 in Bypass Mode

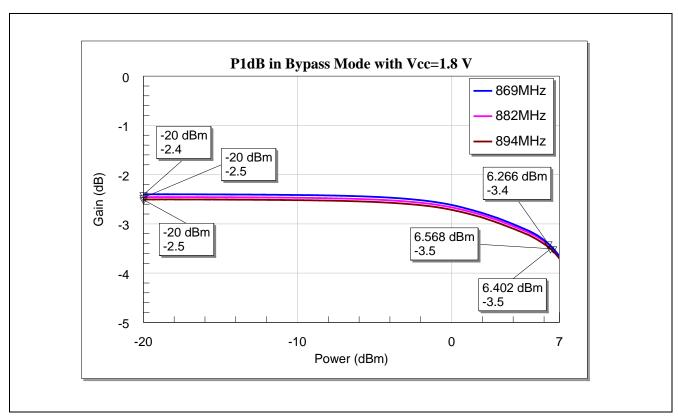


Figure 32 IP1dB of the BGA7L1BN6 for LTE Band 5 in Bypass Mode with 1.8 V power supply



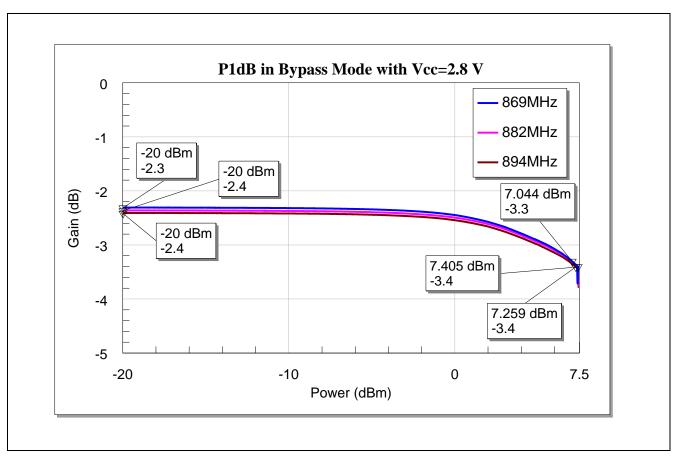


Figure 33 IP1dB of the BGA7L1BN6 for LTE Band 5 in Bypass Mode with 2.8 V power supply

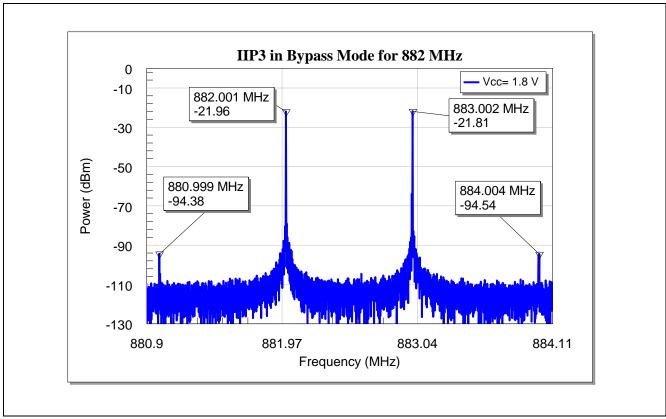


Figure 34 IIP3 of the BGA7L1BN6 for LTE Band 5 in Bypass Mode with 1.8 V power supply



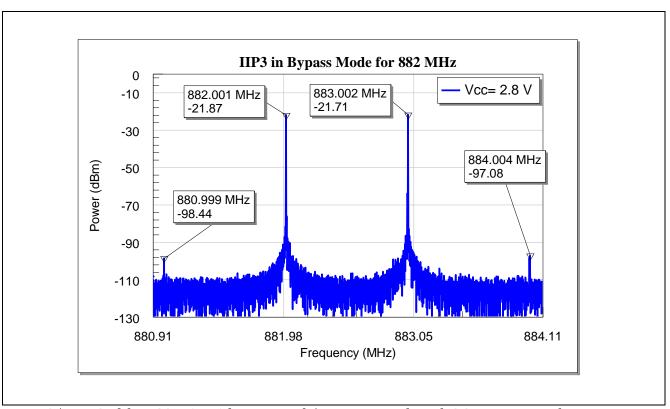


Figure 35 IIP3 of the BGA7L1BN6 for LTE Band 5 in Bypass Mode with 2.8 V power supply



Evaluation Board and Layout Information

5 Evaluation Board and Layout Information

In this application note, the following PCB is used:

PCB Marking: M150429 PCB material: FR4 $\epsilon_{\rm r}$ of PCB material: 4.7

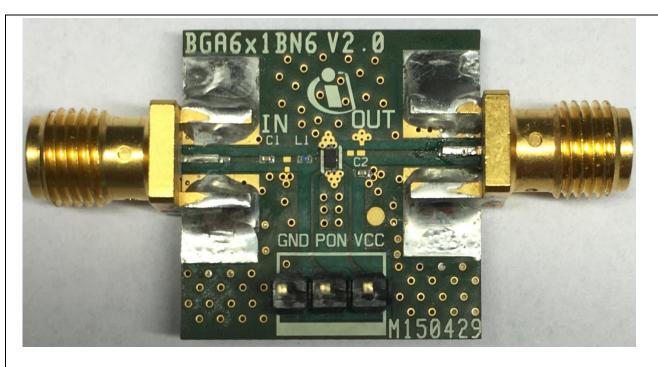


Figure 37 Photo Picture of the Evaluation Board (overview)

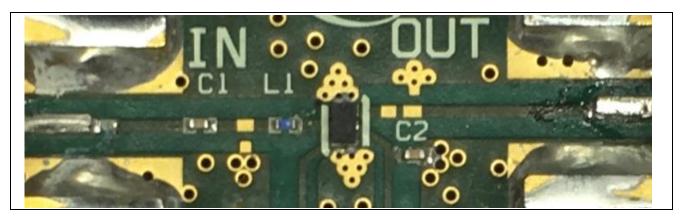


Figure 38 Photo Picture of the Evaluation Board (detailed view)



Evaluation Board and Layout Information

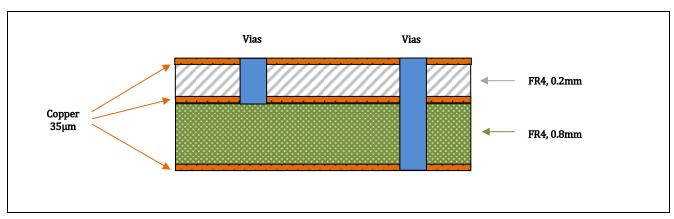


Figure 39 PCB Layer Information



Author

6 Author

Moakhkhrul Islam, RF Application Engineer of Business Unit "Radio Frequency and Sensors"

Puming Fang, Working Student of Business Unit "Radio Frequency and Sensors"

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